Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/780,755	CHEN, DUKE	
Examiner	Art Unit	
Rita Leykin	2837	

SEARCHED					
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Class	Subclass	Date	Examiner		
318	480	4/1/2005	R.L.		
	16				
49	. 28				
342	107				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPAT, DERWENT, EPO, JPO USPGPUB	4/1/2005	R.L.	